

In the United States Patent and Trademark Office

In re the application of
Lee D. Whetsel

Serial No.: 09/955,542

Filed: 9/18/2001

Title: Low Power Scan & Delay Test Method and Apparatus



TI-31727

Art Unit: 2133

Examiner: J. Kerveros Technology Center 2100

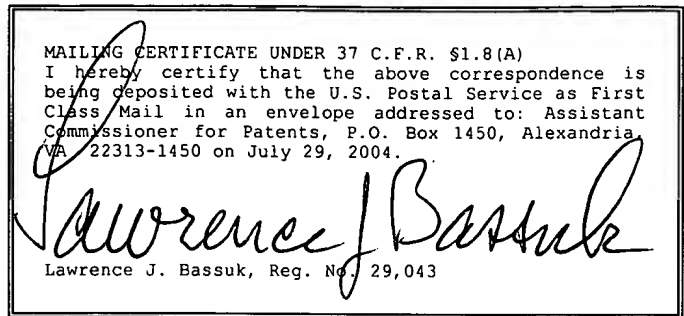
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July 29, 2004

Asst. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313

Dear Sir:



Transmitted herewith is an amendment in this application.

The fee has been calculated as shown below.

CLAIMS AS AMENDED						
	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NUMBER PREVIOUSLY PAID FOR	PRESENT EXTRA	RATE	ADDITIONAL FEE
Total Claims	7	Minus	20	= 0	x \$18 =	\$ 0
Ind. Claims	1	Minus	4	= 0	x \$86 =	\$ 0
TOTAL ADDITIONAL FEE FOR THIS AMOUNT						\$ 0

Under 37 C.F.R. § 1.16(k) please charge the total additional fee, and any further fees, or credit overpayment to Deposit Account No. 20-0668, of Texas Instruments Incorporated.

Respectfully submitted,

Lawrence J. Bassuk

Lawrence J. Bassuk
Reg. No. 29,043
Attorney for Applicant

Texas Instruments Incorporated
P.O. Box 655474, M/S 3999
Dallas, Texas 75265
(972) 917-4418